

<b>Notice of References Cited</b>	Application/Control No. 10/615,955	Applicant(s)/Patent Under Reexamination ONO ET AL.	
	Examiner John D. Lee <i>John D. Lee</i>	Art Unit 2874	Page 1 of 1

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	K	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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